Application/Control	No.

Applicant(s)/Patent under Reexamination KAN, MAKIKO

10/706,238
Examiner

Art Unit

Sun J. Lin

2825

SEARCHED				
Class	Subclass	Date	Examiner	
716	1	2/16/2006	JSL	
716	2-5	2/16/2006	JSL	
712	19	2/16/2006	JSL	
		,		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	1	2/16/2006	JSL
716	2	2/16/2006	JSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST {USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB}	2/16/2006	JSL
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